

Search Notes

Application/Control No.

09/474,783

Examiner

Annan Q. Shang

Applicant(s)/Patent under
Reexamination

NEWELL ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
725	1- 8,88,93,10 2,136	11/2/2005	A.S

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR